

J ournal of I ntegrated C ircuits and S ystems

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FOREWORD

This issue of Journal of Integrated Circuits and Systems (JICS) includes 6 papers on process, materials, devices, and modeling. These papers have been selected from the presentations given at SBMicro2007 (22nd Symposium on Microelectronics Technology and Devices), which has been held in Rio de Janeiro, Brazil in 2007. Among the contributions presented at SBMicro2007 conference, only a few best rated by the reviewers were selected by the JICS Editorial Board and have been invited to submit an extended version. These papers have been submitted to usual reviewing process with the help of external experts.

We would like to thank the authors for their effort in preparing these high quality papers, as well as the reviewers for their help on paper selection, which guarantees the scientific level of this issue. We sincerely hope that JICS readers will enjoy these contributions, as we have enjoyed listening to them at the SBMicro2007 conference.

This year marks a new challenge for JICS as the journal will allow the spontaneous submission of papers additionally to the best papers of Symposium on Microelectronics Technology and Devices and Symposium on Integrated Circuits and Systems Design. We hope the community will support our decision submitting high quality papers that will contribute to the excellence of JICS Journal.

João Antonio Martino
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